

Notice of Allowability	Application No.	Applicant(s)	
	10/621,255	CHET ET AL.	
	Examiner	Art Unit	
	Nitin Parekh	2811	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to 01-12-05.
2. ☒ The allowed claim(s) is/are 1-8, 10-14 and 16-25.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|--|
| 1. <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 6. <input type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date _____. |
| 3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____ | 7. <input checked="" type="checkbox"/> Examiner's Amendment/Comment |
| 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | 8. <input type="checkbox"/> Examiner's Statement of Reasons for Allowance |
| | 9. <input type="checkbox"/> Other _____. |


 Nitin Parekh
 Primary Examiner
 Technology Center 2800

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-8, 10-14 and 16-25 are allowed.

Examiner's Amendment

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

- A. Claim 1, line 8: Delete "the substrate comprised of a dummy layer, a dielectric layer, and a solder mask structure, which encapsulates the dummy layer and the dielectric layer, the substrate mounted on the first surface, the substrate having an aperture where the aperture encompasses the integrated circuit die, and the substrate having and separating a plurality of conduction bands" and insert --- "mounted on the first surface, the substrate having an aperture where the aperture encompasses the integrated circuit die, and the substrate comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction bands entirely encapsulate the dummy layer and the dielectric layer"---.

- B. Claim 18, line 10: Delete: "the substrate having and separating a plurality of conduction bands, and the substrate comprising a dummy layer, a dielectric layer, a solder mask structure which encapsulates the dummy layer and the dielectric layer" and insert --- "the substrate comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction bands entirely encapsulate the dummy layer and the dielectric layer"---.
- C. Claim 25, line 10: Delete: "the substrate means having and separating a plurality of conduction means, and the substrate means comprising a dummy layer, a dielectric layer, a solder mask structure which encapsulates the dummy layer and the dielectric layer" and insert --- "the substrate means comprising a dummy layer, a dielectric layer, a solder mask structure and a plurality of separated conduction bands, wherein the solder mask structure and the plurality of conduction means entirely encapsulate the dummy layer and the dielectric layer"---.

Authorization for this examiner's amendment was given in a telephone interview with Kenneth Oplinger on 10-04-05.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nitin Parekh whose telephone number is 571-272-1663. The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's acting supervisor, Steven Loke can be reached on 571-272-1657. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAN or Public PAG. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAG system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). Any inquiry of a general nature or relating to the

status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

NP

10-05-05



NITIN PAREKH

PRIMARY EXAMINER

TECHNOLOGY CENTER 2800